



AF
JR

IN THE U.S. PATENT AND TRADEMARK OFFICE

April 28, 2008

Applicants : Simon FENNEY et al
Title : TILING SYSTEM FOR 3D RENDERED GRAPHICS
Serial No. : 10/811 071 Group: 2628
Confirmation No.: 8073
Filed : March 26, 2004 Examiner: Hajnik
Atty. Docket No.: 3700.P0373US
Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PETITION FOR TIME EXTENSION, AND CERTIFICATE OF MAILING

Sir:

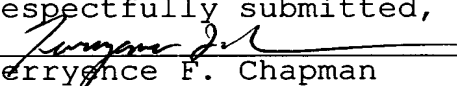
A Response and Notice of Appeal are enclosed.
Pursuant to 37 CFR 1.136(a), please extend the shortened
period for response by one month. The extension fee under 37
CFR 1.17 is \$120.00.

A check for \$630.00 is enclosed to cover fees.

If this Petition is not timely received, please extend
the shortened period an additional month. Please credit any
over-payment, or charge any additional fee required by this
Petition, to Deposit Account No. 06-1382. A duplicate of this
Petition is enclosed.

IN DUPLICATE
TFC/smd

Respectfully submitted,


Terryence F. Chapman

FLYNN, THIEL, BOUTELL
& TANIS, P.C.
2026 Rambling Road
Kalamazoo, MI 49008-1631
Phone: (269) 381-1156
Fax: (269) 381-5465

| | |
|-------------------------|-----------------|
| David G. Boutell | Reg. No. 25 072 |
| Terryence F. Chapman | Reg. No. 32 549 |
| Mark L. Maki | Reg. No. 36 589 |
| Liane L. Churney | Reg. No. 40 694 |
| John A. Waters | Reg. No. 24 802 |
| Brian R. Tumm | Reg. No. 36 328 |
| Donald J. Wallace | Reg. No. 43 977 |
| Stephen C. Holwerda | Reg. No. 57 391 |
| Dale H. Thiel | Reg. No. 24 323 |
| Sidney B. Williams, Jr. | Reg. No. 24 949 |
| Heon Jekal | Reg. No. L0379* |

*limited recognition number

04/30/2008 CCHRU1 00000118 10811071

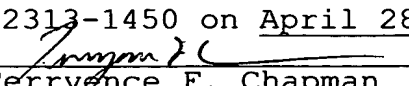
01 FC:1251

120.00 OP

Encl: Check
Response dated April 28, 2008
Notice of Appeal dated April 28, 2008

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450 on April 28, 2008.


Terryence F. Chapman